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IBM PowerPC® 970MP RISC Microprocessor Application Note PowerPC® 970MP Differences

(Includes Differences for 970FX to 970MP)

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1. Abstract

This preliminary application note describes the differences between the PowerPC® 970FX microprocessor and PowerPC 970MP microprocessor. The primary objective of the PowerPC 970FX remap to the 970MP is to achieve a high frequency dual core processor. The design changes include a 1MB L2 cache per core, support for higher bus speeds, power management improvements, and errata fixes.

2. Overview

The IBM 970MP RISC Microprocessor is a dual-core, 64-bit implementation of the IBM PowerPC[®] family of reduced instruction set computer (RISC) microprocessors that are based on the PowerPC Architecture. This dual microprocessor, also called the 970MP, includes a Vector/SIMD facility in each core which supports high-bandwidth data processing and compute-intensive operations. The 970MP is designed to support multiple system organizations, including desktop and low-end server applications, up through 4-way SMP configurations.

The differences between the PowerPC 970FX and 970MP designs are described in the following sections:

- · Process Version Register
- · General Parameters
- Design Enhancements
- · System Design Information
- Timings
- Package

3. Processor Version Register (PVR)

The PowerPC 970FX and 970MP have the following PVR values for the respective design revision levels.

Table 3-1. PowerPC 970FX and 970MP Processor Version Registers (PVR)

Design Revision Level	970FX PVR	970MP PVR
DD1.0	0x00391100	0x00440100
DD1.1	_	0x00440101
DD2.0	0x003C0200	_
DD2.1	0x003C0201	_
DD3.0	0x003C0300	_
DD3.1	0x003C0301	_



4. General Parameters

Table 4-1 provides a summary of the general parameters for the PowerPC 970FX and 970MP.

Table 4-1. General Parameters of the PowerPC 970FX and 970MP

Item	970FX Description	970MP Description
Die Size	66.2 sq. mm	153.8 sq. mm
Die Dimensions	7.07mm x 9.36mm	13.225 mm x 11.629 mm
Transistor Count	52 million	183 Million
Logic Design	Static with some dynamic logic	Static with some dynamic logic
Package	576-pin Ceramic ball grid array (CBGA) 25x25mm (1.0mm pitch)	575-pin Ceramic ball grid array (CBGA) 25x25mm (1.0mm pitch)

5. Design Enhancements for PowerPC 970MP

To create a dual core with improved power savings features, there were several enhancements made to the PowerPC 970MP design.

This section describes the design enhancements to the 970MP.

5.1 Dual Core Design

The 970MP chip consists of two processing units (PUs), each containing an execution core with L1 caches, a storage subsystem including L2 cache, and pervasive functions. In addition, a small amount of common logic that is outside either PU is included to interface each PU to the single bus interface.

The two cores function as would two cores on separate chips for the most part. For example, they maintain memory coherence via the bridge chip, they are able to Doze independently, and they have private access to most processor resources including the L2. Also, like processors on separate chips, they scale frequency, using the power tuning facility, together.

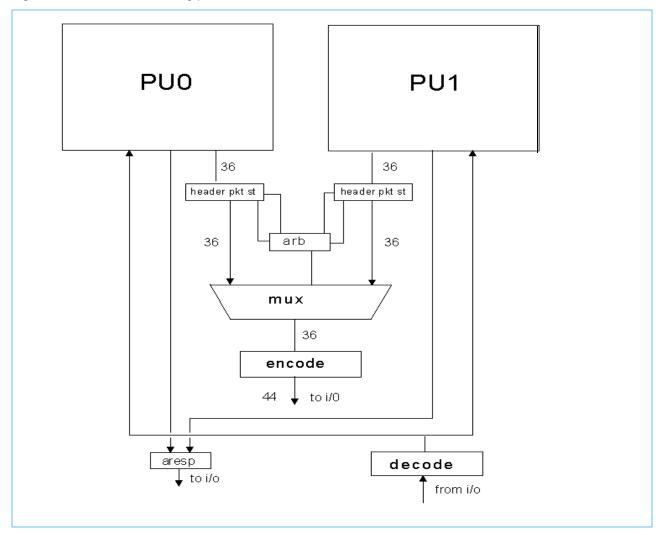
Sharing the same chip constrains the behavior of the two cores in several ways. First, the two PUs have separate voltage planes for power, but the core voltages will always need to be within the delta specified in the *IBM PowerPC 970MP RISC Microprocessor Datasheet* when the two processors are running. Also, the core frequencies will always be the same. This would be true for two separate cores except for the Deep Nap case, where one of two separate processors could reduce frequency to 1/64, while the other ran at functional speed. The two 970MP cores must go into and come out of Deep Nap together.

The other difference between having dual cores on a single chip, versus two separate chips, is that they share a single PI (processor interconnect) interface to the bridge chip. This requires that the interface between the BIU and the PI logic be enhanced with buffers and muxes to support the sharing of the PI interface between the two cores. *Figure 5-1* on page 11 shows the relationship among the two cores and the common logic.

For incoming PI data and commands, the output of the PI decoder is passed directly to both processors. For outgoing PI data and commands, an arbiter and mux are introduced in front of the PI encoder to give one or the other processor access to the outgoing PI bus at any given time. The arbiter implements a round robin

scheme, with provisions for adjusting priorities when one core receives repeated serial retries. Logic in the BIU of each PU is modified to allow the arbiter to hold that PU from sending data to the PI bus when a transaction from the other processor is in progress. The PI bus configuration parameters apply to the single bus, not to the individual processors, and so this arbiter enforces those parameters, such as the COMPACE timing, for example. In order to minimize dead time on the bus, header packets for each processor are queued at the arbiter. Finally, snoop responses from the two processors are combined on chip, and sent as a single response over the PI bus to the bridge chip, as indicated in the lower left corner of *Figure 5-1*.

Figure 5-1. Dual Cores sharing processor interface



The additional logic at the PI/BIU interface requires a SNOOPLAT (and SNOOPACC) value that is larger than for the 970FX, but still within the programmable range. The maximum STATLAT value on 970MP is increased to 30, and it is expected that the bridge chip will need to similarly be designed for a higher maximum value than was previously used. Refer to the *IBM PowerPC 970MP Design Guidelines* for more information.

Intercommunication between the processors on chip occurs in the same way as if they were on separate chips, via the bridge chip. In particular, on-chip L2 to L2 intervention is not supported.



5.1.1 1MB L2 Cache per Core

The 970MP L2 cache design doubles the cache array size and capacity from 970FX, with a corresponding doubling in size of the two copies of the L2 tag arrays. Like the 970FX, it is an 8-way set associative cache of 128 B lines, but now consists of 1024 sets. The latency for L1 misses that hit in the L2 is increased by two processor cycles in the 970MP, due to the longer path from the core to the larger L2 array. This load-use penalty for fixed-point unit operands that hit in the 1 MB L2 cache is 14 processor cycles.



5.2 Processor Interconnect Bus

The 970MP design incorporates an enhanced Processor Interconnect (PI) Interface for its high-speed off-chip bus. There are a number of changes to the physical interface and support hardware associated with the use of the enhanced definition from that in the 970FX. These changes include modifications to the driver and receiver, two new test modes of operation, and additional control and status registers.

5.2.1 SCOM control and status registers

The 970FX contains five 32-bit SCOM registers associated with PI (x'04.6A00', x'0F.6A01', x'0F.7A00', x'04.6B01', x'0F.6B00', and x'0F.7B01'). Three of these are mode registers and two are status registers. See the *IBM PowerPC 970FX RISC Microprocessor User's Manual* for a description of these registers. The 970MP replaces these five SCOM registers with a set of sixteen new SCOM registers (located in the common domain at address x'08.XXXX'). Eight of these are 16-bit registers for fault isolation and error reporting. One is a 16-bit command register for specifying a clock delay. Two are 64-bit IAP registers that allow programming of the IAP pattern. Four are 16-bit mode registers. One is a 16-bit status register. This status register is a read-only register that can be programmed by bits in a mode register (mode register 2, bit 48:54) to return the status of different aspects of the PI interface, depending on the mode register values. These registers are only accessible by the master processing unit. The *IBM PowerPC 970MP Microprocessor User's Manual* describes these registers in detail.

Note in particular the different use of the windage field in the 970MP compared with that in the 970FX. In the 970MP, the windage field is used to add a fixed amount of delay to all bits prior to IAP learning, in order to avoid an underflow when a guardbanding procedure is performed at the end of the IAP.

5.2.2 Test Modes

Two new test modes are supported for bringup of the PI interface. These are the electrical shorts test (EST) and the pseudo-random data test (RDT). The following sections describe both the transmitter and receiver support for these functions.

5.2.2.1 Transmitter Pseudo-Random Data Test (RDT)

One new test feature is the pseudo-random data test mode. This mode uses a built in linear feedback shift register (LFSR) to create pseudo-random patterns to be transmitted across each enabled channel. The LFSR register is 12 bits wide and implements the polynomial $1+x^3+x^5+x^{11}$, using a seed of all 1 bits. These data patterns can then be received and compared to expected patterns created in the receiver core. This mode is described in more detail in the corresponding receiver section. Pseudo-random test mode is enabled by setting the following combination of I/O SCOM mode register 0 bits: WIAP to '1', RDTMODE to '1' and ESTMODE to '0'. The pseudo-random patterns are created as long as this bit combination is set.

5.2.2.2 Transmitter Electrical Shorts Test (EST)

The second new test feature supports a mode which allows the integrity of the off-chip link to be tested to verify its electrical integrity - that is, to find opens and shorts between channels. In support of this feature, the transmitter core can create specific patterns that are then verified in the receiver core. Described below are the patterns created by the transmitter for this mode. This mode is described in detail in the corresponding receiver section. In short test mode, the transmitter creates a pattern of 16 consecutive data '1' bits on serial data channel 0, while all other channels are transmitting '0' bits. After 16 bit times, the next sequential channel will transmit a data '1' for 16 bit times, while the previously enabled channel and all other channels



are transmitting '0' bits. This process repeats itself until the 16 consecutive '1' bits have been walked in sequence across all channels. The electrical shorts test mode is enabled by setting the following I/O SCOM mode register 0 bits: ESTMODE to '1', WIAP to '1', and RDTMODE to '1'. Once enabled the shorts test will create the sequential patterns across all data channels, and then will stop. However, if any of the values of the three mode bits that enable this mode are changed, the test will be terminated immediately. Once a test is complete the SCOM mode bit WIAP must be deasserted and reasserted to start a new test.

The electrical shorts test also has a feature controlled by SCOM mode bit ESTONE. Holding ESTONE at a '1' creates the pattern sequence previously described. Forcing ESTONE to a '0' reverses the values of the pattern sequence, essentially creating a walking '0' sequence across a field of data 1's.

5.2.2.3 Receiver Electrical Shorts Test (REST)

The transmitter mode called electrical shorts test, which creates a walking '1' or walking '0' pattern, is discussed in the transmitter description. For the test to be performed correctly both the transmitter and receiver within the link must have the same ESTONE value applied. Mismatched ESTONE values results in a failing test.

The walking pattern appears on the data channels as the walking data value on the channel under test, surrounded by the opposite data value on all other channels in the data field. The walking data value is held on a given channel for 16 bit times, after which the data value for that channel is returned to the data value of the field, and the walking value is applied to the next channel for 16 bit times. The process is continued until all channels have been tested.

Each channel is independently forced to a '1' while the field is '0'. Each time a channel is tested by applying a data '1' the receiver checks to see that the channel under test, and only the channel under test, observes the '1'. If at any time more than one channel is received as a '1', a short between the channel under test and other channel(s) observing a '1' exists. If any channel under test fails to observe the '1' an error on that channel is indicated.

The following is the process for performing the shorts test:

- 1. Configure receiver in bypass mode, SCOM mode reg BYPASS=1.
- 2. Force transmitter to send data '0' on all channels if ESTONE=1, or send data '1' on all channels if ESTONE=0.
- 3. Wait for receiver to be flushing 0's or 1's, as appropriate.
- 4. Start receiver SCOM mode reg ESTMODE and RIAP set active.
- 5. Start transmitter SCOM mode reg ESTMODE and WIAP set active.
- 6. Receiver status reports errors if test fails.

Note that the link does not require IAP training before the shorts test is run. However, for the test to be successful the receiver must be configured in bypass mode which flushes data through the FIFO within the receiver. This bypass mode is entered by forcing the SCOM mode register BYPASS bit to '1' before the test is initiated. The receiver initiates the test by observing all received data channels, and samples data on all channels after the leading edge of the first data transition on channel 0 is observed. This creates a sampling strobe approximately in the center of the 16 bits of data on the channel under test. The checking procedure within the receiver expects the channel under test to increment from channel 0 through channel 47.



If the expected results are not observed, an error is flagged in the status register. The DIAG_RDT vector out of the receiver provides observability of individual channel failures. The status register, bit 1, also indicates that the shorts test is complete. Completion of the shorts test within a reasonable period of time should be verified after the test is initiated with SCOM mode reg ESTMODE and WIAP.

5.2.2.4 Receiver Random Data Self Test

Also discussed in the transmitter description is the Pseudo-Random Data Test (RDT). The receiver also has an LFSR register built into it, that is capable of duplicating the pseudo-random test patterns that were sent across the link from the transmitter core. Preceding the random pattern across the link is a solid 0 value. When the random data self test is initiated within the receiver by enabling the SCOM mode reg RDTMODE and RIAP, the receiver self-test logic monitors the data received, and when a transition from the solid '0' value to a '1' is observed, the receiver LFSR register begins to generate patterns which are then compared to the received data. Once initiated, the random data self-test procedure continues until RDTMODE and RIAP are disabled.

The following is the process for performing a link random data self test:

- 1. Train the receiver.
- 2. Force the transmitter to send data 0's.
- 3. Wait for the receiver to be flushing 0's.
- 4. Start receiver SCOM mode reg RDTMODE and RIAP set active.
- 5. Start transmitter SCOM mode reg RDTMODE and WIAP set active (starts the test).
- 6. Receiver status reports errors if the test fails.

If the expected results are not observed on any channel, an error is flagged in the status register. The DIAG_RDT vector out of the receiver provides observability of any channel which did not contain expected values for the duration of the test. Unlike the shorts test previously described, the status register will never indicate completion of the test, as there is no predefined end to the random data sequence.

For status information to remain valid at the termination of a test, the random data self test should be terminated by deasserting RIAP at the receiver prior to deasserting WIAP at the transmitter. However, since there is no indication that the random data self test ever started within the receiver, WIAP can be deasserted first, which provokes errors on all receiver channels upon its deassertion. Status and DIAG_RDT should be monitored before deasserting WIAP to verify that there are no failing channels prior to its deassertion.

The LFSR data sent across the link represents data with a rich mix of data transitions that are much more random than the IAP training pattern, and therefore stress the link alignment beyond the point that it was stressed during IAP. A link which successfully completes IAP may still suffer from bit errors when random data is transferred across the link. Random data self test allows the link to be evaluated for proper alignment before real data is sent across the link.

5.2.3 Bus Configuration

The larger L2 caches, the bus arbiter between the two cores, and the use of the PI receiver design combine to introduce additional delay in the path between the L2 cache and the bus interface. In particular, the PI receiver adds one bus beat of delay, and the bus arbiter adds another bus beat of delay on incoming signals. The bus arbiter adds two bus beats of delay on the outgoing signals. This results in an additional four bus beats of latency for a snoop response, for example. The programmable delay parameters described in



Section 11.4 of the 970FX User's Manual are set to system dependent values during initialization, and must account for these larger latencies in the 970MP. The range of values that may be specified for each of these parameters for the 970MP is:

Table 5-1. PowerPC 970MP Programmable Delay Parameters

Parameter	Min.	Max
COMPACE	2	14
STATLAT	4	30
SNOOPLAT	6	12
SNOOPACC	9	24

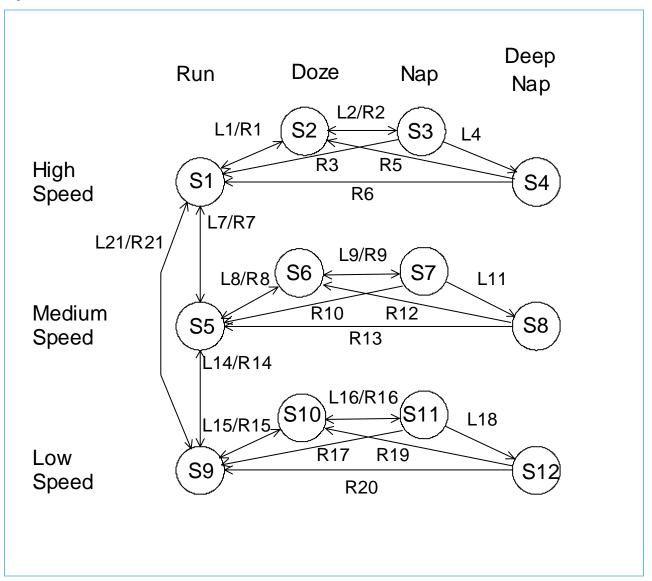
In addition, the definitions of STATLAT, SNOOPLAT, and SNOOPACC in 970MP have changed due to additional staging of bus signals internally. Thus, setting a STATLAT value of 24 in the register corresponds to a delay of 22 bus beats between the last beat of the ADO packet and the first beat of the transfer-handshake packet. Similarly, a value two larger than the actual bus delay must be programmed into the SNOOPLAT and SNOOPACC registers on 970MP.

5.3 PowerTuning

5.3.1 Power Modes

The twelve power states associated with the power tuning engine frequency scaling facility on the 970MP are indicated by the nodes S1 through S12 in *Figure 5-2*.

Figure 5-2. 970MP Power Modes



The state diagram in *Figure 5-2* represents two changes for the 970MP design. First, the Deep Nap state can be reached from the Nap state at any frequency. Second, frequency scaling between full and quarter frequency can be done directly.

Table 5-2 describes the twelve power mode states.

Table 5-2. Power Mode States

State	Description
S1	Full Run, High Speed
S2	Doze, High Speed
S3	Nap, High Speed
S4	Deep Nap, High
S5	Full Run, Medium Speed
S6	Doze, Medium Speed
S7	Nap, Medium Speed
S8	Deep Nap, Medium
S9	Full Run, Low Speed
S10	Doze, Low Speed
S11	Nap, Low Speed
S12	Deep Nap, Low

5.3.2 Time Base and Decrementer

The time base and decrementer registers will run at a constant frequency, independent of changes to the processor and bus frequencies. For 970FX, the default operation of these timers is to run at 1/8 the full processor frequency, even when the processor itself is running at a lower frequency. For 970MP, the default operation of these timers is to run at 1/16 the full processor frequency, even when the processor itself is running at a lower frequency. When TBEN is configured to clock these timers (HID0[19] = 1), the timers will run at the TBEN frequency. In this case, the maximum allowable TBEN frequency is 1/16 the full processor frequency.

Since the mesh clock frequency can be lowered to 1/64th of the full-speed, the time base/decrementer may be increased/decreased by more than one at a time. Therefore testing that the decrementer has reached the value of zero in order to generate an internal interrupt is not sufficient. The logic detects that the counter has wrapped around. Additionally the time resolution of the counters is limited by the mesh clock frequency.

5.4 I²C Bus Interface

5.4.1 Clock Dithering (New feature for 970FX DD3.0, enhanced in 970MP)

Input current to the processor can change significantly during power tuning frequency transitions. These current changes must be controlled in order to avoid over and under-voltages that large di/dt might cause due to inductance in the power distribution network. In DD3.0 of the 970FX, a clock dithering mechanism was added in the power tuning hardware, to gradually transition between frequencies. The 970MP replaces the 970FX 24-bit dither with a selectable 24- or 48-bit dither pattern.



The transition from quarter to full frequency is handled in two stages. First, the processor is transitioned from quarter frequency to half frequency using the quarter to half dither pattern. The processor is paused for 32 cycles at half frequency, and then transitioned to full frequency using the half to full dither pattern. A similar procedure is used for the full to quarter frequency transition.

5.4.2 Programmable Delays for Power Saving Mode Transitions

The 970MP design introduces a programmable delay when transitioning between power saving modes, to reduce di/dt in these cases. For example on interrupt, the processor transitions from Deep Nap, through Nap and Doze, to Run. The latency is a combination of fixed (full frequency) and mesh clock cycles, plus a programmable delay. The programmable delay, Dp, is controlled by a 6-bit mode ring value. Dp specifies the number of full frequency cycles of delay from 0 to 63. This delay occurs 6 times during the Deep Nap to Run transition.

Table 5-3 lists the latency of Deep Nap to Run Transition for the PowerPC 970MP for full, half, and quarter frequency scaling.

Table 5-3. PowerPC 970MP Latency of Deep Nap to Run Transition (Full Frequency Cycles)

Full	Half	Quarter
123 + 6*Dp	228 + 6*Dp	438 + 6*Dp

5.5 Additional Dynamic Power Management

To a limited extent the PowerPC 970 design implements dynamic power management (DPM) – the gating of clocks to idle circuits while in an operational mode. For example, clocks in the pipelined vector processing units (VPUs) are gated on a stage by stage basis, as instructions flow through the pipeline. The 970FX design implements additional dynamic power management in the STS, IDU, and RAS units. The 970MP design implements additional dynamic power management in the ISU, FXU, and FPU units.

Dynamic power management can be disabled as follows. For the VPU, IDU and STS, DPM is disabled by negating HID0[DPM]. For the ISU, FXU, FPU and pervasive units, DPM is disabled by setting bit 0 in JTAG register 0x00.0800 to a '1'.

5.6 More Precise Kelvin Circuitry

The 970MP implements circuitry that enables more precise Kelvin measurements. This increased precision allows for better correlation between the Kelvin signals and the actual voltage applied to the transistors. However, this improved precision in the Kelvin pins also increased their sensitivity. For DD1.0, DD1.01, DD1.02, the maximum allowable current is 0.9mA. For DD1.1, the maximum allowable current is 2.7mA. Exceeding these maximum currents may cause permanent damage to the microprocessor. Oscilloscope probes should provide enough impedance to prevent excess current on these pins. Due to ESD concerns, this change was reversed back to the 970FX implementation for DD1.03 and DD1.11+. For additional details, refer to the *IBM PowerPC 970MP RISC Microprocessor Datasheet*.

6. System Design Information

The 970MP supports a 24:1 bus ratio for test purposes instead of the 16:1 bus ratio supported in the 970FX. The BUS_CFG(0:2) pin setting for this 24:1 bus ratio is '110', which is the same setting that was used to select the 16:1 bus ratio in the 970FX.

Unlike the 970FX, ANALOG_GND is not shorted to GND within the 970MP. Please refer to the *IBM PowerPC 970MP RISC Microprocessor Datasheet* for the proper filtering recommendation.

7. Timings

Note: Timings are very processor and technology specific. It should not be assumed that timings remain equivalent between any of the PowerPC microprocessors designs. Timings for each of the IBM PowerPC microprocessor family of products are located within their specific electrical specification, referred to as the "Datasheet." Contact your IBM Sales or technical support group for the *PowerPC 970MP RISC Microprocessor Datasheet*.

8. Package

8.1 Design Considerations for a 970MP Thermal Solution

The 970MP package differs from the 970FX with respect to:

- Die size/dimension
- · Position of the capacitors on the die

8.1.1 Die Size

A thermal solution for the 970MP needs to consider the die size (refer to *Table 8-1* and *Figure 8-1*). Due to a higher power density, heat pipes may be stressed and pushed quite close to their boiling point. If the liquid in the pipe boils, the cooling system will fail. The PowerPC 970MP is on the cusp of air versus water for a cooling solution.

Table 8-1. PowerPC 970FX, and 970MP Die Size and Dimensions

	970FX	970MP
Die size	66.2 sq mm	153.8 sq mm
Die Dimension	7.07mm x 9.36mm	13.23mm x 11.63mm

8.1.2 Capacitor Position

The 970MP capacitors are rotated 90 degrees compared to the 970FX capacitor layout with respect to the A01 corner. This occurred since the PLL moved 90 degrees with respect to A01 and due to the die size of the 970MP - wider in the x direction than the 970FX because of the additional core. This change will be an important design consideration if the thermal solution is orientation dependant.

8.2 Description of Signal Changes

Most of the pins on the 970MP are the same as those found on the 970FX package, though the pin placement is different. However, there are a number of pins that are duplicated, one per core, several new or modified pins, and a few deletions.

Table 8-2 lists the duplicated 970FX pins, one per core on the PowerPC 970MP. *Table 8-3* lists the new PowerPC 970MP pins. *Table 8-4* lists 970FX pins not found on PowerPC 970MP.

Table 8-2. 970FX Pins Duplicated for each 970MP Processing Unit

970FX	970MP Core0	970MP Core1	Function
HRESET_B	CP0_HRESET_B	CP1_HRESET_B	Hard Reset
SRESET_B	CP0_SRESET_B	CP1_SRESET_B	Soft Reset
ĪNT_B	CP0_INT_B	CP1_INT_B	External Interrupt
QACK_B	CP0_QACK_B	CP1_QACK_B	Quiesce Acknowledge
QREQ_B	CP0_QREQ_B	CP1_QREQ_B	Quiesce Request
DIODE_NEG	CP0_DIODE_NEG	CP1_DIODE_NEG	Thermal Diode Terminal
DIODE_POS	CP0_DIODE_POS	CP1_DIODE_POS	Thermal Diode Terminal
KVPRBVDD	CP0_KELV_V0	CP1_KELV_V1	Kelvin Voltage (V _{DD}) Monitor
KVPRBGND	CP0_KELV_GND0	CP1_KELV_GND1	Kelvin Voltage (GND) Monitor

Table 8-3. New 970MP Pins

970MP New Pin	Function
KELV_OVDD	Kelvin Voltage (OV _{DD}) Monitor
KELV_GND2	Kelvin Voltage (GND) Monitor
MASTERSEL	Select PU0 as master, tie to GND.
I2CSEL	Allows external selection of the I2C or JTAG interface for controlling scan functionality
CP0_FRED_EN	IBM MFG Test Only
CP0_FRED_GND	IBM MFG Test Only
CP1_FRED_EN	IBM MFG Test Only
CP1_FRED_GND	IBM MFG Test Only

Table 8-4. Deleted 970FX Pins - not found on 970MP

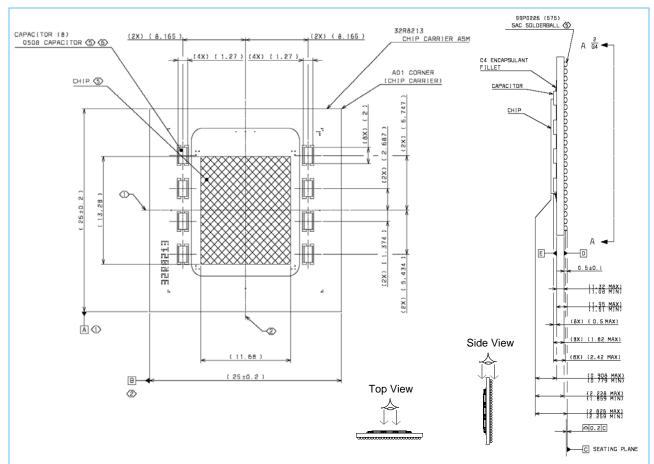
970FX Pin	970FX Function
PROCID2	Least significant bit in the 3 bit processor ID, automatically set on PowerPC 970MP
THERM_INT_B	Dedicated thermal interrupt signal, removed due to lack of use
TRIGGERIN	Initiate trace collection from outside, removed due to lack of use
PSYNC_OUT	Used to check phase alignment while debugging, removed due to lack of use
SPARE_GND	Unneeded Spare

8.3 PowerPC 970MP Microprocessor Package Dimensions

IBM offers the 970MP in a ceramic ball grid array, CBGA, package which supports 575 balls. The 970MP is offered in a lead reduced package with SnAgCu (SAC) balls. The following figures contain views of the 970MP package.

Figure 8-1 shows the side and top views of the Pb-reduced package including the height from the top of the die to the bottom of the solder balls. Figure 8-2 shows a bottom view of the PowerPC 970MP package.

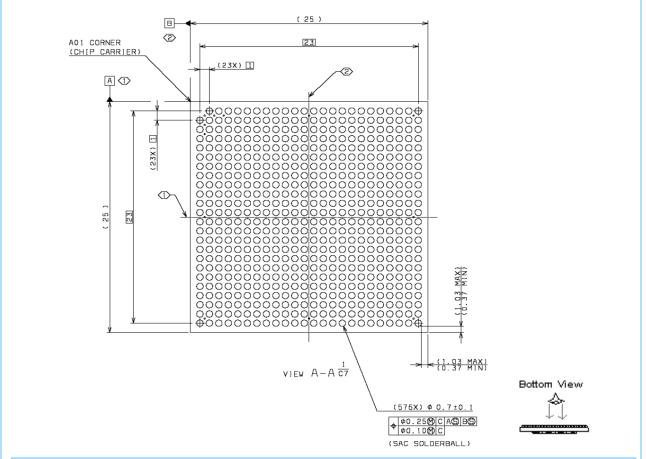
Figure 8-1. PowerPC 970MP Mechanical Package (Side and Top View)



Legend		
	<u>(1)</u>	DATUM A is the center plane of feature labeled DATUM A.
	(2)	DATUM B is the center plane of feature labeled DATUM B.
	3	Unless otherwise specified part is symmetrical about centerlines defined by DATUMs A and B.
	4	Where not otherwise defined, centerlines indicated are to be interpreted as a datum frame work, established by DATUMS D, A, and B respectively.
	(7)	This line defines the approximate boundary configuration of encapsulant as dispensed. For underfill requirements see IBM Engineering Specification 71X8781 Module Encapsulation Specification.
	9	The chip's assembled height (which include silicon thickness and melted C4) for 300mm wafers is: 0.829mm - 0.908mm. The 300mm silicon thickness is 0.785mm +/- 0.020mm.



Figure 8-2. PowerPC 970MP Bottom Surface of CBGA Package (Bottom View)



Leg	Legend		
(1	1	DATUM A is the center plane of feature labeled DATUM A.	
(2	2 >	DATUM B is the center plane of feature labeled DATUM B.	
3	3	Unless otherwise specified part is symmetrical about centerlines defined by DATUMs A and B.	
4	4	Where not otherwise defined, centerlines indicated are to be interpreted as a datum frame work, established by DATUM D, A, and B, respectively.	
<u> </u>	7>	This line defines the approximate boundary configuration of encapsulant as dispensed. For underfill requirements see IBM Engineering Specification 71X8781 Module Encapsulation Specification.	
9	9	The chip's assembled height (which include silicon thickness and melted C4) for 300mm wafers is: 0.829mm - 0.908mm. The 300mm silicon thickness is 0.785mm +/- 0.020mm.	



Revision Log

Revision	Modification
November 15, 2006	Version 1.0 Initial preliminary version.